Lot Acceptance Test (LAT) Data

1. Unless otherwise specified on the purchase order, the Seller shall provide lot acceptance test (LAT) data in accordance with the applicable contract requirements with each shipment. The test data shall contain information such that the test data is traceable to the hardware tested and being presented for acceptance. Appropriate information such as part number, revision letter, Purchase Order number, supplier name, lot number/code, etc., shall be used. Unless otherwise stated, (LAT) samples and test data shall NOT be shipped in advance of the hardware.

2. In all cases, sample selection for (LAT) shall be a random sample selected for the total population of chips comprising a single inspection lot. The actual sample size and any special criteria shall be in accordance with the associated specifications. In the case of an inspection lot comprised of more than one wafer, it is NOT acceptable to select all samples for a single wafer. NOTE: the use of a random number table is encouraged. Wafers from the same wafer/manufacturing lot which are NOT included in the population sample are not considered part of the qualified lot, i.e., they require random sampling for (LAT) as a new inspection lot.

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